



NanoLab Delivers!

Glossary of Terms

**Analytical
Services**

• AES	Auger Electron Spectroscopy
• AFM	Atomic Force Microscopy
• AEM	Analytical Transmission Electron Microscopy
• C-SAM	C-Mode Scanning Acoustic Microscopy
• C-SOM	C-Mode Scanning Optical Microscopy
• CE-FIB	Circuit Edit - Focused Ion Beam
• D-SIMS	Dynamic - Secondary Ion Mass Spectrometry
• E-SEM	Environmental - Scanning Electron Microscopy
• EDS	Energy-Dispersive (X-Ray) Spectrometry (aka EDX)
• EELS	Electron Energy Loss Spectrometr
• ESCA	Electron Spectroscopy for Chemical Analysis (aka XPS)
• FE-SEM	Field Emission - Scanning Electron Microscopy
• FE-TEM	Field Emission - Transmission Electron Microscopy
• FIB	Focused Ion Beam
• FIB-SEM	Focused Ion Beam - Scanning Electron Microscopy
• FMI	Fluorescent Microscopy Imaging
• FT-IR	Fourier Transform Infra-Red Spectroscopy
• GD-MS	Glow Discharge - Mass Spectrometry
• GD-OES	Glow Discharge - Optical Emission Spectroscopy
• ICP-MS	Inductively Coupled Plasma - Mass Spectrometry
• ICP-OES	Inductively Coupled Plasma - Optical Emission Spectroscopy
• P-FIB	Plasma - Focused Ion Beam
• RAMAN	Raman Spectroscopy
• SEM	Scanning Electron Microscopy
• SIMS	Secondary Ion Mass Spectrometry
• STEM	Scanning Transmission Electron Microscopy
• TDR	Time Domain Reflectometry
• TEM	Transmission Electron Microscopy
• TOF-SIMS	Time-of-Flight - Secondary Ion Mass Spectrometry
• TXRF	Total Reflection X-Ray Fluorescence
• VASE	Variable Angle Spectroscopic Ellipsometry
• WD-XRF	Wavelength Dispersive X-ray Fluorescence
• UHR	Ultra High Resolution
• XPS	X-Ray Photoelectron Spectroscopy (aka ESCA)
• XRD	X-Ray Diffraction
• XRR	X-Ray Reflectometry

**Analytical Services
On Demand**

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